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Sheet 1 of 1 Attorney Docket Number 386998041US

Complete If Known

Application Number	10/731,517-Conf. #3730
Filing Date	December 9, 2003
First Named Inventor	Erik S. Jeng
Art Unit	2815
Examiner Name	E. Lee

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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NON PATENT LITERATURE DOCUMENTS					
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EL	CA	Jeng, Erik S. et al, "Investigation of Programming Charge Distribution in Nonoverlapped Implantation nMOSFETs", IEEE Trans. Electron Devices, Vol. 53, no. 10, pp. 2517-2524, Oct. 2006.			
CL	CB	Luksy, E. et al, "Investigation of channel hot electron injection by localized charge-trapping nonvolatile memory devices," IEEE Trans. Electron Devices, vol. 51, no. 3, pp. 444-451, Mar. 2004.			
CC	CC	Makwana, Jitu J. et al, "A Nonvolatile Memory Overview". (website: http://aplawrence.com/Makwana/nonvolmem.html).			

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